



Giga Test Labs

Serving the Electronics Industry with Engineering Excellence



Dual Probes

GTL Microwave Probes were developed to provide superior electrical performance and unparalleled durability when used for probing on wafer, package, BGA, PCB, socket, backplane, high density interconnect, etc. The ruggedized probe tips extend the life of the probes

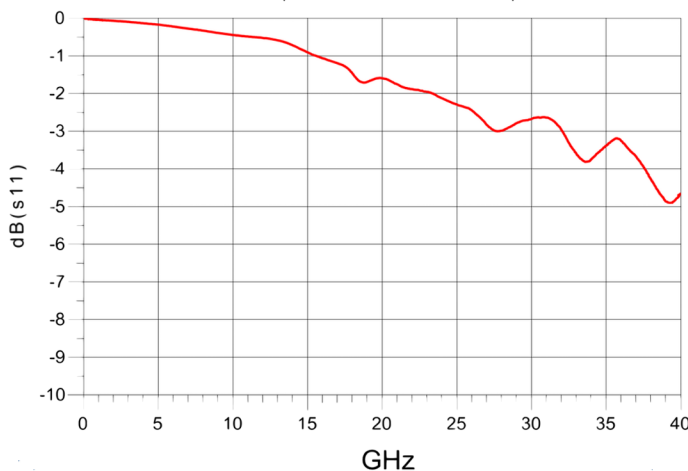
Electrical Characteristics:

- 50 Ohm Impedance
- DC to 40 GHz Frequency Range
- -15 dB Return Loss
- 1.5 dB Insertion Loss

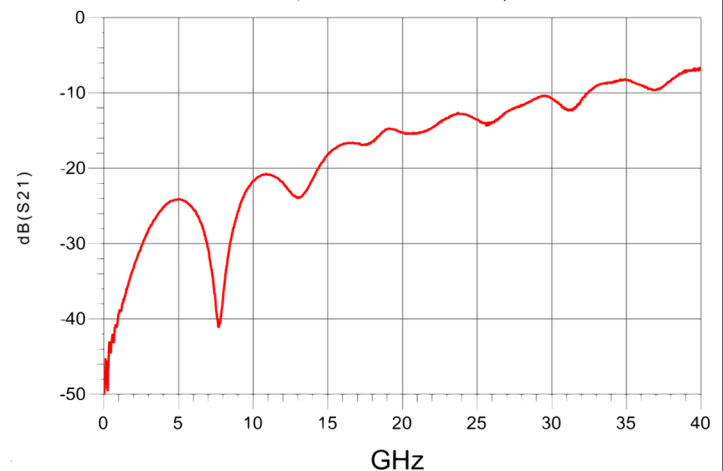
Mechanical Characteristics:

- Probe Tip Configurations: GSSG
- 2.92 mm connector that is mechanically compatible with:
 - SMA Cables
 - 3.5 mm Cables
 - 2.92 mm Cables
- Maximum Connector Torque: •10 inch-lbs
- Gold Plated Probe Tips
- Standard Pitches: 200 μ , 250 μ , 300 μ , 450 μ , 500 μ , 600 μ , 750 μ , 1000 μ
Custom Pitches Available
- Signal to Signal Pitch is adjustable from 200 μ -1500 μ

GTL40-750-GSSG-DX S/N 1290 GS
LOG MAG | Insertion Loss dB | 1 dB/DIV



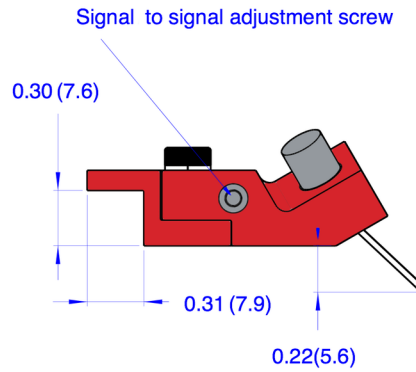
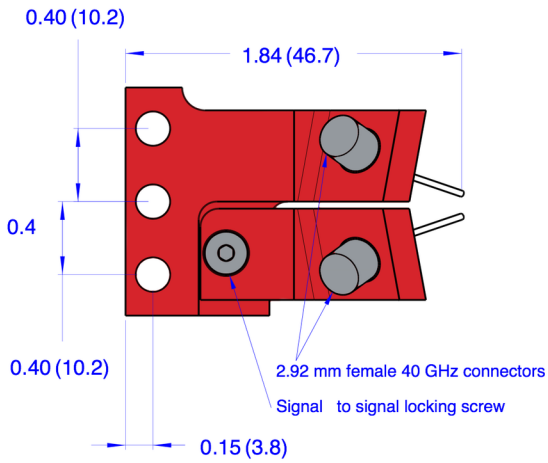
GTL40-750-GSSG-DX S/N 1290 GS
LOG MAG | Return Loss dB | 10 dB/DIV



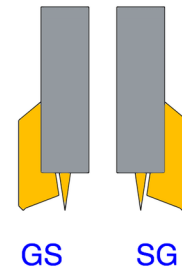


GTL 40 GHz RF Probes

Dual Probe Mechanical Outline



PROBE TIP CONFIGURATION



双程科技公司
SE TECHNOLOGIES CORP.



KEYSIGHT
TECHNOLOGIES

Solutions Partner



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